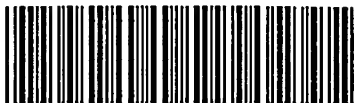


# Search Notes



Application/Control No.

10/660,821

Examiner

Kin-Chan Chen

Applicant(s)/Patent under  
Reexamination

YEH ET AL.

Art Unit

1765

## SEARCHED

Class	Subclass	Date	Examiner
438	270	5/31/2005	K-CC
	283		
	585		
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	706		
	719		
	721		
	745		
	754		
438	755	5/31/05	K-CC

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST key words search, USPAT, US-PGPUB, EPO, JPO, Derwent, IBM-TDB, inventor search	5/31/2005	K-CC